

REVISIONS																			
LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED																
A	Change in accordance with NOR 5962-R181-95.	95-08-07	K. A. Cottongim																
B	Changes to table I.	99-03-16	K. A. Cottongim																

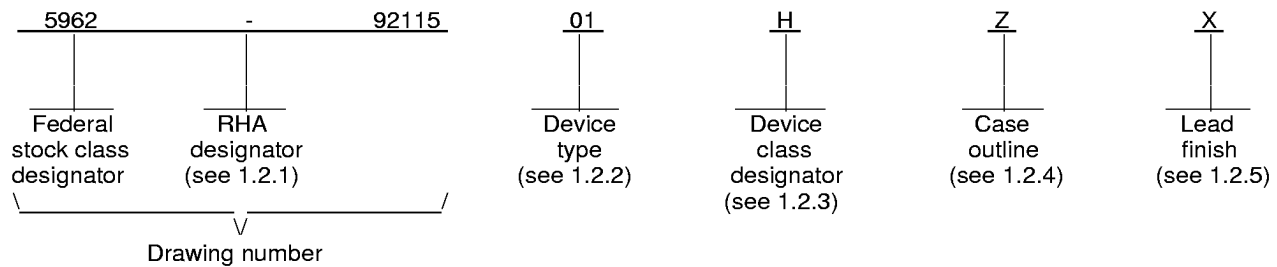
  

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REV STATUS OF SHEETS				REV		B	B	B	B	B	B	B	B	B	B				
				SHEET		1	2	3	4	5	6	7	8	9	10	11			
PMIC N/A				PREPARED BY Steve L. Duncan						<b>DEFENSE SUPPLY CENTER COLUMBUS</b> <b>P. O. BOX 3990</b> <b>COLUMBUS, OHIO 43216-5000</b>									
<b>STANDARD MICROCIRCUIT DRAWING</b>  THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE  AMSC N/A				CHECKED BY Michael C. Jones															
				APPROVED BY Kendall A. Cottongim															
				DRAWING APPROVAL DATE 92-11-16															
								REVISION LEVEL  B						SIZE <b>A</b>		CAGE CODE <b>67268</b>		<b>5962-92115</b>	
										SHEET		1		OF		11			

## 1. SCOPE

1.1 Scope. This drawing documents five product assurance classes, class D (lowest reliability), class E, (exceptions), class G (lowest high reliability), class H (high reliability), and class K, (highest reliability) and a choice of case outlines and lead finishes are available and are reflected in the Part or Identifying Number (PIN). When available, a choice of radiation hardness assurance levels are reflected in the PIN.

1.2 PIN. The PIN shall be as shown in the following example:



1.2.1 Radiation hardness assurance (RHA) designator. Device classes H and K RHA marked devices shall meet the MIL-PRF-38534 specified RHA levels and shall be marked with the appropriate RHA designator. A dash (-) indicates a non-RHA device.

1.2.2 Device type(s). The device type(s) shall identify the circuit function as follows:

<u>Device type</u>	<u>Generic number</u>	<u>Circuit function</u>
01	AHV2812T/CH	DC/DC converter, 15 W, +5 V and ±12 V outputs

1.2.3 Device class designator. This device class designator shall be a single letter identifying the product assurance level as follows:

<u>Device class</u>	<u>Device performance documentation</u>
D, E, G, H or K	Certification and qualification to MIL-PRF-38534

1.2.4 Case outline(s). The case outline(s) shall be as designated in MIL-STD-1835 and as follows:

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
Z	See figure 1	10	Flange mount

1.2.5 Lead finish. The lead finish shall be as specified in MIL-PRF-38534.

1.3 Absolute maximum ratings. 1/

Input voltage range . . . . .	-0.5 V dc to +50 V dc (continuous), +80 V dc (100 ms)
Power dissipation (P <sub>D</sub> ) . . . . .	10 W
Lead temperature (soldering, 10 seconds) . . . . .	+300°C
Storage temperature range . . . . .	-65°C to +150°C

1/ Stresses above the absolute maximum rating may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.

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#### 1.4 Recommended operating conditions.

Input voltage range .....	+16 V dc to +40 V dc
Output currents:	
+5 V output .....	2000 mA
±12 V output .....	±208 mA
Output power <u>1/</u> <u>2/</u> .....	≤ 15 W
Case operating temperature range (T <sub>C</sub> ) .....	-55° C to +125° C

#### 2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, and handbook. The following specification, standards, and handbook form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those listed in the issue of the Department of Defense Index of Specifications and Standards (DoDISS) and supplement thereto, cited in the solicitation.

##### SPECIFICATION

###### DEPARTMENT OF DEFENSE

MIL-PRF-38534 - Hybrid Microcircuits, General Specification for.

##### STANDARDS

###### DEPARTMENT OF DEFENSE

MIL-STD-883 - Test Methods and Procedures for Microelectronics.  
MIL-STD-973 - Configuration Management.  
MIL-STD-1835 - Microcircuit Case Outlines.

##### HANDBOOK

###### DEPARTMENT OF DEFENSE

MIL-HDBK-780 - Standard Microcircuit Drawings.

(Unless otherwise indicated, copies of the specification, standards, and handbook are available from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

#### 3. REQUIREMENTS

3.1 Item requirements. The individual item performance requirements for device classes D, E, G, H, and K shall be in accordance with MIL-PRF-38534. Compliance with MIL-PRF-38534 may include the performance of all tests herein or as designated in the device manufacturer's Quality Management (QM) plan or as designated for applicable device class. Therefore, the tests and inspections herein may not be performed for applicable device class (see MIL-PRF-38534). Furthermore, the manufacturers may take exceptions or use alternate methods to the tests and inspections herein and not perform them. However, the performance requirements as defined in MIL-PRF-38534 shall be met for the applicable device class. The modification in the QM plan shall not affect the form, fit, or function as described herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38534 and herein.

1/ Derate output power linearly above case temperature +125° C to 0 at +135° C.

2/ At least 25 percent of the total power should be from the main (+5 volt) output.

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3.2.1 Case outline(s). The case outline(s) shall be in accordance with 1.2.4 herein and figure 1.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 2.

3.2.3 Block diagram. The block diagram shall be as specified on figure 3.

3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full specified operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are defined in table I.

3.5 Marking of device(s). Marking of device(s) shall be in accordance with MIL-PRF-38534. The device shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's vendor similar PIN may also be marked as listed in QML-38534.

3.6 Data. In addition to the general performance requirements of MIL-PRF-38534, the manufacturer of the device described herein shall maintain the electrical test data (variables format) from the initial quality conformance inspection group A lot sample, for each device type listed herein. Also, the data should include a summary of all parameters manually tested, and for those which, if any, are guaranteed. This data shall be maintained under document revision level control by the manufacturer and be made available to the preparing activity (DSCC-VA) upon request.

3.7 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to supply to this drawing. The certificate of compliance (original copy) submitted to DSCC-VA shall affirm that the manufacturer's product meets the performance requirements of MIL-PRF-38534 and herein.

3.8 Certificate of conformance. A certificate of conformance as required in MIL-PRF-38534 shall be provided with each lot of microcircuits delivered to this drawing.

#### 4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-PRF-38534 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein.

4.2 Screening. Screening shall be in accordance with MIL-PRF-38534. The following additional criteria shall apply:

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DSCC-VA or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.

(2)  $T_C$  as specified in accordance with table I of method 1015 of MIL-STD-883.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions -55°C ≤ T <sub>C</sub> ≤ +125°C V <sub>IN</sub> = 28 V dc ±5%, C <sub>L</sub> = 0 unless otherwise specified	Group A subgroups	Device types	Limits		Unit
					Min	Max	
Output voltage <u>1/</u>	V <sub>OUT</sub>	I <sub>OUT</sub> = 0 (main)	1	01	4.95	5.05	V
			2,3		4.90	5.10	
		I <sub>OUT</sub> = 0 (dual)	1		±11.88	±12.12	
			2,3		±11.76	±12.24	
Output current <u>1/ 2/ 3/</u>	I <sub>OUT</sub>	V <sub>IN</sub> = 16, 28, and 40 V dc (main)	1,2,3	01	100	2000	mA
		V <sub>IN</sub> = 16, 28, and 40 V dc (dual)	1,2,3		0.0	±208	
Output ripple voltage <u>1/ 4/</u>	V <sub>RIP</sub>	V <sub>IN</sub> = 16, 28, and 40 V dc B.W. = 20 Hz to 2 MHz (main)	1,2,3	01		80	mV p-p
		V <sub>IN</sub> = 16, 28, and 40 V dc B.W. = 20 Hz to 2 MHz (dual)	1,2,3			40	
Line regulation <u>1/ 3/</u>	V <sub>RLINE</sub>	V <sub>IN</sub> = 16, 28, and 40 V dc I <sub>OUT</sub> = 100, 1000, and 2000 mA (main)	1,2,3	01		±25	mV
		V <sub>IN</sub> = 16, 28, and 40 V dc I <sub>OUT</sub> = 0, ±104, and ±208 mA (dual)	1			±30	
			2,3			±60	
Load regulation <u>1/ 3/</u>	V <sub>RLOAD</sub>	V <sub>IN</sub> = 16, 28, and 40 V dc I <sub>OUT</sub> = 100, 1000, and 2000 mA (main)	1,2,3	01		±50	mV
		V <sub>IN</sub> = 16, 28, and 40 V dc I <sub>OUT</sub> = 0, ±104, and ±208 mA (dual)				±60	
Input current	I <sub>IN</sub>	I <sub>OUT</sub> = 0, inhibit (pin 8) tied to input return (pin 10)	1,2,3	01		15	mA
		I <sub>OUT</sub> = 0, inhibit (pin 8) = open				50	
Input ripple current <u>4/</u>	I <sub>RIP</sub>	I <sub>OUT</sub> = 2000 mA (main) I <sub>OUT</sub> = ±208 mA (dual) B.W. = 20 Hz to 2 MHz	1,2,3	01		50	mA p-p

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C ≤ T <sub>C</sub> ≤ +125°C V <sub>IN</sub> = 28 V dc ±5%, C <sub>L</sub> = 0 unless otherwise specified	Group A subgroups	Device types	Limits		Unit
					Min	Max	
Efficiency	E <sub>FF</sub>	I <sub>OUT</sub> = 2000 mA (main) I <sub>OUT</sub> = ±208 mA (dual)	1	01	72		%
			2,3		68		
Isolation	ISO	Input to output or any pin to case (except pin 7) at 500 V dc, T <sub>C</sub> = +25°C	1	01	100		MΩ
Power dissipation load fault <u>3/</u>	P <sub>D</sub>	Overload <u>5/</u>	1,2,3	01		10	W
		Short circuit				10	
Switching frequency <u>1/</u>	F <sub>S</sub>	I <sub>OUT</sub> = 2000 mA (main) I <sub>OUT</sub> = ±208 mA (dual)	4,5,6	01	450	550	kHz
Inhibit open circuit voltage	V <sub>OI</sub>		1,2,3	01	9	13	V
Output response to step transient load changes <u>6/</u>	V <sub>O</sub> T <sub>LOAD</sub>	50 percent load to/from 100 percent load	4	01	-300	+300	mV pk
			5,6		-400	+400	
		Minimum load to/from 50 percent load	4		-400	+400	
			5,6		-600	+600	
Recovery time step transient load changes <u>6/ 7/</u>	T <sub>T</sub> LOAD	50 percent load to/from 100 percent load	4	01		100	μs
			5,6			200	
		Minimum load to 50 percent load	4,5,6			2000	
		50 percent load to minimum load	4,5,6			5000	
Output response to transient step line changes <u>8/ 9/</u>	V <sub>O</sub> T <sub>LINE</sub>	Input step 16 from/to 40 V dc, I <sub>OUT</sub> = 2000 mA (main) I <sub>OUT</sub> = ±208 mA (dual)	4,5,6	01		±1500	mV pk
Recovery time transient step line changes <u>7/ 8/ 9/</u>	T <sub>T</sub> LINE	Input step 16 from/to 40 V dc, I <sub>OUT</sub> = 2000 mA (main) I <sub>OUT</sub> = ±208 mA (dual)	4,5,6	01		5	ms

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C ≤ T <sub>C</sub> ≤ +125°C V <sub>IN</sub> = 28 V dc ±5%, C <sub>L</sub> = 0 unless otherwise specified	Group A subgroups	Device types	Limits		Unit
					Min	Max	
Load fault recovery <u>9/</u>	TR <sub>LF</sub>		4,5,6	01		15	ms
Turn on overshoot <u>1/</u>	VTON <sub>OS</sub>	I <sub>OUT</sub> = 100 and 2000 mA (main) I <sub>OUT</sub> = 0 and ±208 mA (dual)	4,5,6	01		750	mV pk
Turn on delay <u>1/ 10/</u>	TON <sub>D</sub>	I <sub>OUT</sub> = 100 and 2000 mA (main) I <sub>OUT</sub> = 0 and ±208 mA (dual)	4,5,6	01		15	ms

- 1/ Tested at each output.  
2/ Parameter guaranteed by line and load regulation tests.  
3/ At least 25 percent of the total output power should be taken from the (+5 volt) main output.  
4/ Bandwidth guaranteed by design. Tested for 20 kHz to 2 MHz.  
5/ An overload is that condition with a load in excess of the rated load but less than that necessary to trigger the overload protection circuit and is the condition of maximum power dissipation.  
6/ Load step transition time between 2 and 10 microseconds.  
7/ Recovery time is measured from the initiation of the transient to where V<sub>OUT</sub> has returned to within ±1 percent of V<sub>OUT</sub> at 50 percent load.  
8/ Input step transition time between 2 and 10 microseconds.  
9/ Parameter shall be tested as part of design characterization and after design or process changes. Thereafter parameters shall be guaranteed to the limits specified in table 1.  
10/ Turn on delay time measurement is for either a step application of power at the input or the removal of a ground signal from the inhibit pin (pin 8) while power is applied to the input.

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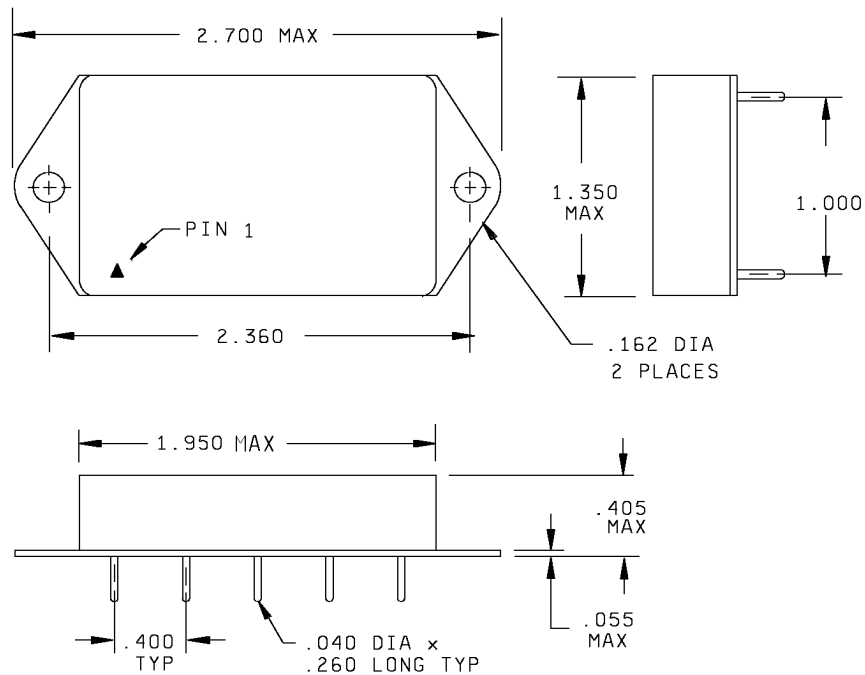
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Case outline Z.



Inches	mm
0.005	0.13
0.040	1.02
0.055	1.40
0.162	4.12
0.260	6.60
0.400	10.16
0.405	10.29
1.000	25.40
1.350	34.29
1.950	49.53
2.360	59.94
2.700	68.58

NOTES:

1. Dimensions are in inches.
2. Metric equivalents are for general information only.
3. Unless otherwise specified, tolerance is  $\pm 0.005$ .
4. Case outline Z weight: 76 grams maximum.

FIGURE 1. Case outline(s).

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Device type	01
Case outline	Z
Terminal number	Terminal symbol
1	Positive input
2	+5 V dc output
3	Output return
4	-12 V dc output
5	+12 V dc output
6	No connection
7	Case ground
8	Inhibit input
9	No connection
10	Input return

FIGURE 2. Terminal connections.

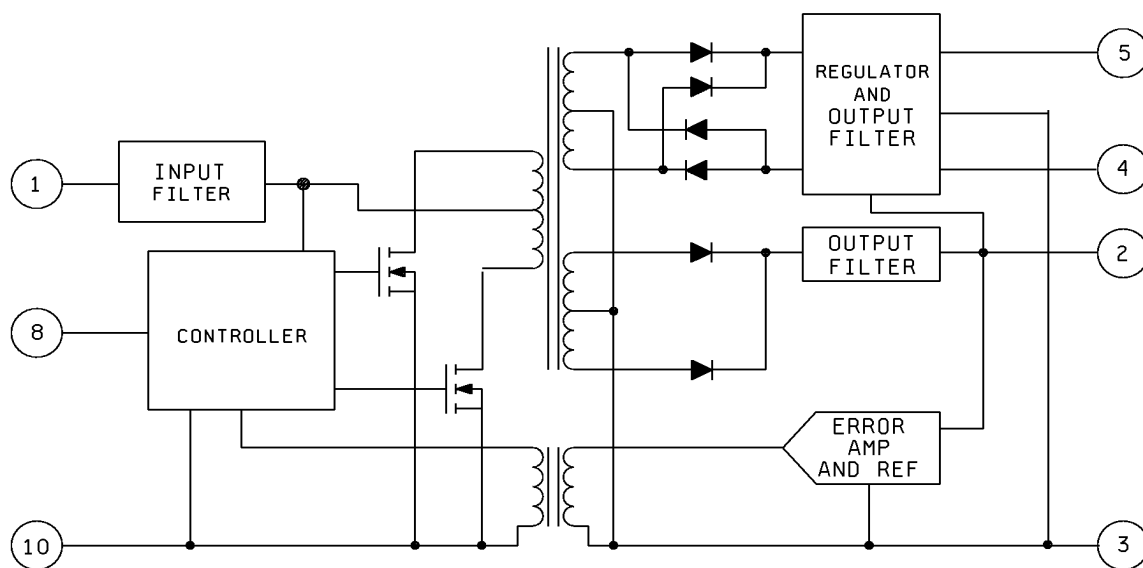


FIGURE 3. Block diagram.

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TABLE II. Electrical test requirements.

MIL-PRF-38534 test requirements	Subgroups (in accordance with MIL-PRF-38534, group A test table)
Interim electrical parameters	---
Final electrical parameters	1*, 2, 3, 4, 5, 6
Group A test requirements	1, 2, 3, 4, 5, 6
Group C end-point electrical parameters	1, 4
MIL-STD-883, group E end-point electrical parameters for RHA devices	Subgroups** (in accordance with method 5005, group A test table)

\* PDA applies to subgroup 1.

\*\* When applicable to this standard microcircuit drawing,  
the subgroups shall be defined.

4.3 Conformance and periodic inspections. Conformance inspection (CI) and periodic inspection (PI) shall be in accordance with MIL-PRF-38534 and as specified herein.

4.3.1 Group A inspection (CI). Group A inspection shall be in accordance with MIL-PRF-38534 and as follows:

- a. Tests shall be as specified in table II herein.
- b. Subgroups 7, 8, 9, 10, and 11 shall be omitted.

4.3.2 Group B inspection (PI). Group B inspection shall be in accordance with MIL-PRF-38534.

4.3.3 Group C inspection (PI). Group C inspection shall be in accordance with MIL-PRF-38534 and as follows:

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test, method 1005 of MIL-STD-883.
  - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DSCC-VA or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.
  - (2)  $T_C$  as specified in accordance with table I of method 1005 of MIL-STD-883.
  - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

4.3.4 Group D inspection (PI). Group D inspection shall be in accordance with MIL-PRF-38534.

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4.3.5 Group E inspection. Group E inspection is required only for parts intended to be marked as radiation hardness assured (see 3.5 herein). RHA levels for device classes H and K shall be M, D, R, and H. RHA quality conformance inspection sample tests shall be performed at the RHA level specified in the acquisition document.

- a. RHA tests for device classes H and K for levels M, D, R, and H shall be performed through each level to determine at what levels the devices meet the RHA requirements. These RHA tests shall be performed for initial qualification and after design or process changes which may affect the RHA performance of the device.
- b. End-point electrical parameters shall be as specified in table II herein.
- c. Prior to total dose irradiation, each selected sample shall be assembled in its qualified package. It shall pass the specified group A electrical parameters in table I for subgroups specified in table II herein.
- d. For device classes H and K, the devices shall be subjected to radiation hardness assured tests as specified in MIL-PRF-38534 for RHA level being tested, and meet the postirradiation end-point electrical parameter limits as defined in table I at  $T_A = +25^\circ\text{C} \pm 5$  percent, after exposure.
- e. Prior to and during total dose irradiation testing, the devices shall be biased to establish a worst case condition as specified in the radiation exposure circuit.
- f. For device classes H and K, subgroups 1 and 2 in table V, method 5005 of MIL-STD-883 shall be tested as appropriate for device construction.
- g. When specified in the purchase order or contract, a copy of the RHA delta limits shall be supplied.

## 5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38534.

## 6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-973 using DD Form 1692, Engineering Change Proposal.

6.4 Record of users. Military and industrial users shall inform Defense Supply Center Columbus when a system application requires configuration control and the applicable SMD. DSCC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DSCC-VA, telephone (614) 692-7603.

6.5 Comments. Comments on this drawing should be directed to DSCC-VA, P. O. Box 3990, Columbus, Ohio 43216-5000, or telephone (614) 692-0676.

6.6 Sources of supply. Sources of supply are listed in QML-38534. The vendors listed in QML-38534 have submitted a certificate of compliance (see 3.7 herein) to DSCC-VA and have agreed to this drawing.

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# STANDARD MICROCIRCUIT DRAWING SOURCE APPROVAL BULLETIN

DATE: 99-03-16

Approved sources of supply for SMD 5962-92115 are listed below for immediate acquisition only and shall be added to QML-38534 during the next revision. QML-38534 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DSCC-VA. This bulletin is superseded by the next dated revision of QML-38534.

Standard microcircuit drawing PIN <u>1</u> /	Vendor CAGE number	Vendor similar PIN <u>2</u> /
5962-9211501HZA	52467	AHV2812TF/CH

- 1/ The lead finish shown for each PIN, representing a hermetic package, is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the Vendor to determine availability.
- 2/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE  
number

52467

Vendor name  
and address

Lambda Advanced Analog, Incorporated  
2270 Martin Avenue  
Santa Clara, CA 95050-2781

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in this information bulletin.